

I Claim:

1. A circuit for detecting a focused ion beam attack,
comprising:

a memory cell;

an antenna for detecting an FIB attack connected to said
memory cell;

a driver circuit; and

a capacitance connected between said memory cell and said
driver circuit, for isolating said driver circuit from said
antenna.

2. The circuit according to claim 1, wherein said memory cell
is a memory cell selected from the group consisting of a
floating gate cell, an EEPROM cell, a flash cell, and a SONOS
cell.

3. The circuit according to claim 1, wherein said memory cell
comprises an electrically conductive electrode over a silicon
area.

4. The circuit according to claim 1, wherein said memory cell
is one of two memory cells connected to said antenna and
isolated from said driver circuit by said capacitance.

5. The circuit according to claim 1, connected for operation as a FIB sensor of a smart card IC.